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DATE: Monday, October 25, 2004

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<input type="checkbox"/>	L17		((emulation or debug or test\$4) near3 mode) and ((activat\$4 or initiat\$4) near5 (power near2 management near2 functions))	1
<input type="checkbox"/>	L16		(determin\$4 near3 (emulation or debug or test\$4) near3 mode) and ((activat\$4 or initiat\$4) near5 (power near2 management near2 functions))	0
<input type="checkbox"/>	L15		(determin\$4 near3 (emulation or debug or test\$4) near3 mode) same ((activat\$4 or initiat\$4) near5 (power near2 management near2 functions))	0
<input type="checkbox"/>	L14		L8 same (subset or portion or partial\$4 or fragment\$4 or section)	13
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<input type="checkbox"/>	L12		l8 same (test or debug or emulation)	20
<input type="checkbox"/>	L11		l5 and l8	0
<input type="checkbox"/>	L10		(activat\$4 or initiat\$4) near5 functions near5 (based or depend\$4 or accord\$4 or respons\$4) near5 (mode near2 flag)	0
<input type="checkbox"/>	L9		(activat\$4 or initiat\$4) near5 functions near5 (based or depend\$4 or accord\$4 or respons\$4) near5 (mode near2 bit)	0
<input type="checkbox"/>	L8		(activat\$4 or initiat\$4) near5 functions near5 (based or depend\$4 or accord\$4 or respons\$4) near5 mode	121
<input type="checkbox"/>	L7		(command adj data) with (specify\$4 near5 mode)	14
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<input type="checkbox"/>	L3		(subset with functions) same ((based or depend\$4 or accord\$4 or respons\$4) near5 emulat\$4)	0
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L12: Entry 11 of 20

File: USPT

Aug 17, 1999

DOCUMENT-IDENTIFIER: US 5940783 A

TITLE: Microprocessor and method of testing the same

Detailed Description Text (6) :

(2) Prior to the activation of the normal operation function, the activation control function 105 is activated, which then determines, based on the status of the mode identifying means, whether to activate the test implement function 103 or the normal operation function.

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L7: Entry 3 of 14

File: USPT

May 17, 1994

DOCUMENT-IDENTIFIER: US 5313297 A

TITLE: System for providing pictures responding to users' remote control

Detailed Description Text (8):

The command buffer 41 includes a random-access memory (RAM), and memorizes the command data from the DTMF signal conversion device 30, temporarily. The command analysis device 42 including an encoder reads the command data in sequence from the command buffer 41, and analyzes them, and then outputs the command data to the switching signal generation device 43 in case where the command data are for specifying the program, or outputs the command data to the control signal generation device 44 in case where the command data are for specifying the operation mode of the picture reproducing equipment 60.

Detailed Description Text (22):

Next, the command data specifying the operation mode are read from the command buffer 41 and analyzed by the command analysis device 42, and then the command data are outputted from the command data analysis device 42 to the control signal generation device 44. Then, the operation control signals are outputted to the control signal switching equipment 50, and then outputted through the switch of the control signal switching equipment 50 to the picture reproducing equipment 60 which stores the program specified by the user, and the picture reproducing equipment 60 is operated in the specified mode by the operation control signals. The picture signals from the picture reproducing equipment 60 are outputted to the picture coding equipment 90 through the switch of the picture switching equipment 80, and are converted into the picture data by the picture coding equipment 90, and then transmitted to the corresponding ISDN line.

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L7: Entry 1 of 14

File: USPT

Mar 16, 2004

DOCUMENT-IDENTIFIER: US 6708044 B1

TITLE: Apparatus and method for automated band selection via synthesizer bit insertion

CLAIMS:

1. A method for providing band selection in a communication apparatus with band to band operating capability, the communication apparatus including a receiver section, a transmitter section, a frequency synthesizer and a controller, the method comprising: receiving a frequency command data signal, the frequency command data signal used for deriving a bit stream, the bit stream including a frequency data word defining a synthesizer operating frequency and at least one functional bit for specifying a mode of operation; extracting the functional bit from the bit stream to generate an operational signal; providing the operational signal to the receiver section to modify operation thereof; and, utilizing the frequency data word to further modify operation of the communication apparatus.

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L7: Entry 12 of 14

File: JPAB

Jul 4, 1995

DOCUMENT-IDENTIFIER: JP 07169271 A

TITLE: SEMICONDUCTOR STORAGE DEVICE, CLOCK-SYNCHRONOUS TYPE SEMICONDUCTOR DEVICE AND OUTPUT CIRCUIT

Abstract Text (1):

PURPOSE: To provide a cache DRAM provided with a command register capable of driving an output control signal at a high speed, storing the command data specifying many operation modes and internal conditions in a smaller occupation area and writing/reading from the outside.

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L12: Entry 2 of 20

File: USPT

Dec 2, 2003

DOCUMENT-IDENTIFIER: US 6657901 B2

TITLE: Semiconductor device formed in a rectangle region on a semiconductor substrate including a voltage generating circuit

Detailed Description Text (50):

In the test mode, the test circuit is activated to set the test functions in response to a specific address signal fed at that time.

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L12: Entry 16 of 20

File: USPT

May 30, 1995

DOCUMENT-IDENTIFIER: US 5420869 A
TITLE: Semiconductor integrated circuit device

Brief Summary Text (3):

The present invention generally relates to semiconductor integrated circuit devices, and more particularly to a semiconductor integrated circuit device in which the test functions of a built-in test circuit are activated in response to a test mode setting signal, which is applied to an external connection terminal and is higher than a voltage applied thereto in a normal operation mode.

Brief Summary Text (4) :

Recently, semiconductor integrated circuit devices have been designed to have advanced functions and an increased integration density. It takes an extremely long time to test such semiconductor integrated circuit devices in order to detect defects introduced during the production process. Under the above circumstances, a semiconductor integrated circuit device with a built-in test circuit has been developed in which the test functions of a built-in test circuit are activated in response to a test mode setting signal, which is applied to an external connection terminal and is higher than a voltage applied thereto in a normal operation mode.

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L12: Entry 18 of 20

File: USPT

Feb 17, 1987

DOCUMENT-IDENTIFIER: US 4644541 A

** See image for Certificate of Correction **

TITLE: Diagnostic test for programmable device in a mailing machine

Brief Summary Text (6) :

Briefly, according to one embodiment of the invention, apparatus for diagnostic testing of the contents of a programmable device in an automatic mailing machine is provided comprising control panel means, having a plurality of control switches and a visual display, for controlling the mailing machine functions in a normal mode of operation, and means for initiating a test mode in response to activating a selected key of the control panel means. In addition, means are provided for summing the contents of the programmable device to obtain a total sum value responsive to initiation of the test mode. Alternatively, the total sum value may be displayed on a visual display, or means may be provided to compare the total sum value to a predetermined check sum value and display an error indication in response to a difference.

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